

- Dependable Texas Instruments Quality and Reliability

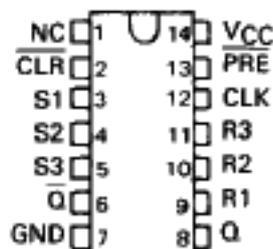
description

This R-S flip-flop circuit is based on the master-slave principle. The AND gate inputs for entry into the master section are controlled by the clock pulse. The clock pulse also regulates the state of the coupling transistors which connect the master and slave sections. The sequence of operation is as follows:

1. Isolate slave from master
2. Enter information from AND gate inputs to master
3. Disable AND gate inputs
4. Transfer information from master to slave

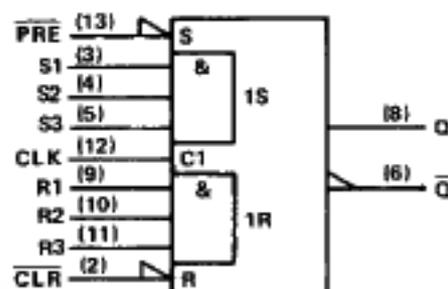
The SN54L71 is characterized for operation over the full military temperature range of -55°C to 125°C .

SN54L71 . . . J PACKAGE
 (TOP VIEW)



NC - No internal connection

logic symbol



Pin numbers shown are for J packages.

FUNCTION TABLE

| INPUTS | | | | | OUTPUTS | |
|--------|-----|-----|---|---|----------------|-----------------|
| PRE | CLR | CLK | S | R | Q | Q̄ |
| L | H | X | X | X | H | L |
| H | L | X | X | X | L | H |
| L | L | X | X | X | H [†] | H [†] |
| H | H | | L | L | Q ₀ | Q̄ ₀ |
| H | H | | H | L | H | L |
| H | H | | L | H | L | H |
| H | H | | H | H | INDETERMINATE | |

[†] This configuration is nonstable; that is, it will not persist when preset and clear inputs return to their inactive (high) level.

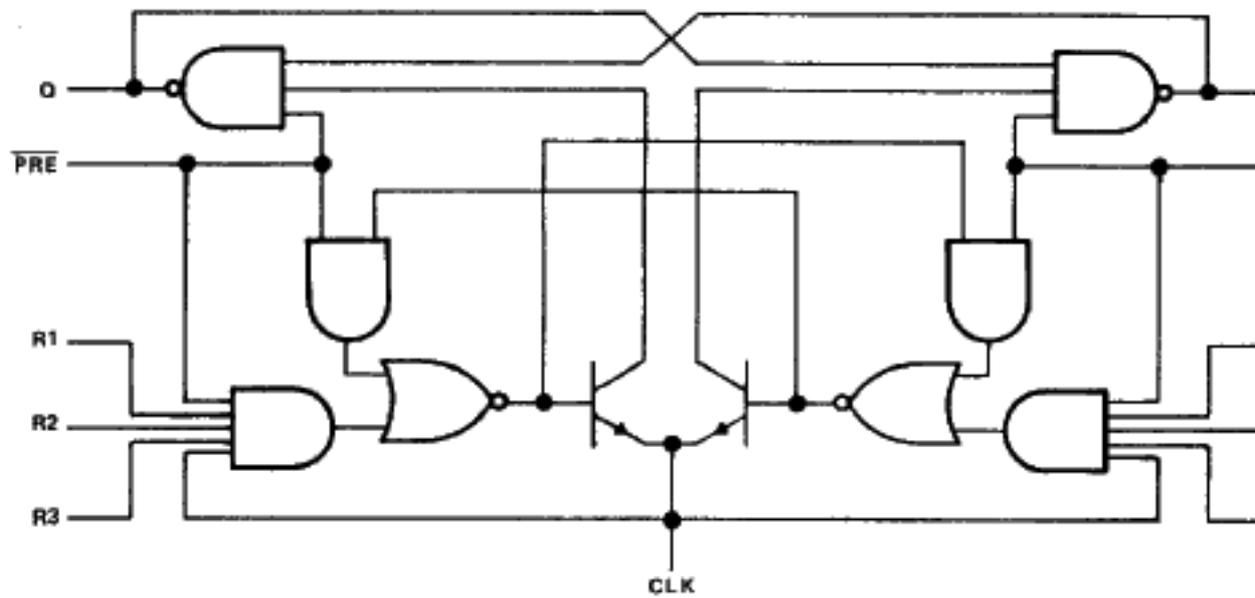
positive logic

$$R = R1 \cdot R2 \cdot R3$$

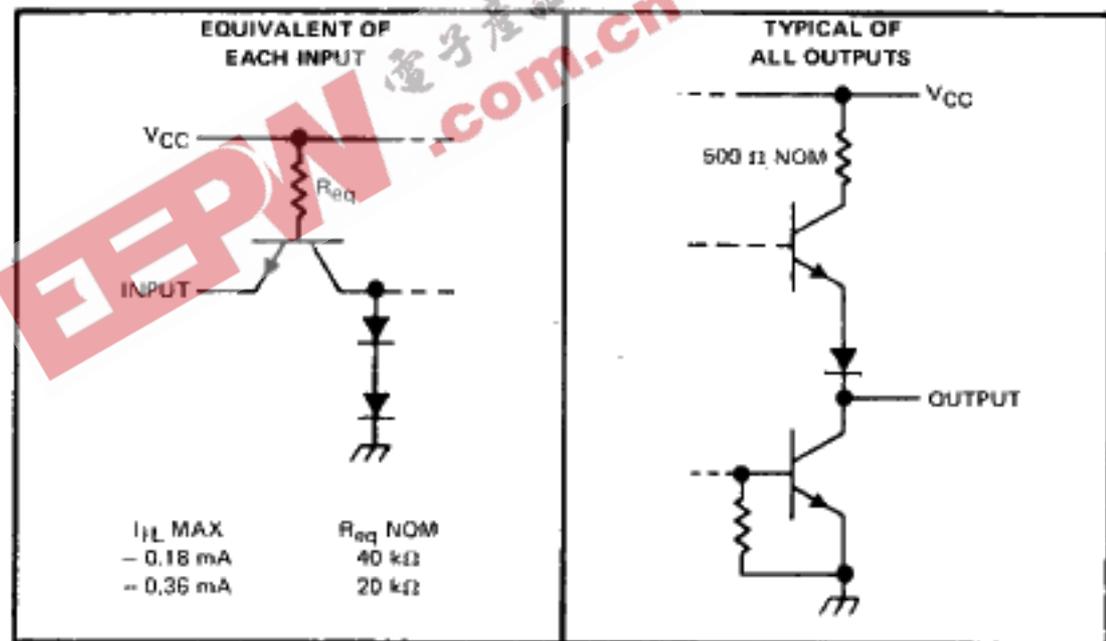
$$S = S1 \cdot S2 \cdot S3$$

**TYPE SN54L71
AND-GATED R-S MASTER-SLAVE
FLIP-FLOPS WITH PRESET AND CLEAR**

logic diagram



schematics of input and outputs



3

TTL DEVICES

TYPE SN54L71 AND-GATED R-S MASTER-SLAVE FLIP-FLOPS WITH PRESET AND CLEAR

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

| | |
|---|----------------|
| Supply voltage, V_{CC} (see Note 1) | 7 V |
| Input voltage | 5.5 V |
| Operating free-air temperature | -55°C to 125°C |
| Storage temperature range | -65°C to 150°C |

NOTE 1: Voltage values are with respect to network ground terminal.

recommended operating conditions

| | | MIN | NOM | MAX | UNIT |
|----------|--------------------------------|-----------------|-----|------|------|
| V_{CC} | Supply voltage | 4.5 | 5 | 5.5 | V |
| V_{IH} | High-level input voltage | 2 | | | V |
| V_{IL} | Low-level input voltage | | | 0.6 | V |
| | | | | 0.7 | |
| I_{OH} | High-level output current | | | -0.1 | mA |
| I_{OL} | Low-level output current | | | 2 | mA |
| t_w | Pulse duration | CLK high or low | 200 | | ns |
| | | PRE or CLR low | 100 | | |
| t_{su} | Setup time before CLK † | 0 | | | ns |
| t_h | Hold time-data after CLK † | 0 | | | ns |
| T_A | Operating free-air temperature | -55 | | 125 | °C |

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

| PARAMETER | TEST CONDITIONS † | MIN | TYP ‡ | MAX | UNIT |
|-----------|--|--|-------|-------|---------------|
| V_{OH} | $V_{CC} = \text{MIN.}$, $V_{IH} = 2 \text{ V.}$, $V_{IL} = \text{MAX.}$, $I_{OH} = -0.1 \text{ mA}$ | 2.4 | 3.3 | | V |
| V_{OL} | $V_{CC} = \text{MIN.}$, $V_{IH} = 2 \text{ V.}$, $V_{IL} = \text{MAX.}$, $I_{OL} = 2 \text{ mA}$ | | 0.15 | 0.3 | V |
| I_I | R or S | | | 0.1 | mA |
| | All other | $V_{CC} = \text{MAX.}$, $V_I = 5.5 \text{ V}$ | | 0.2 | |
| I_{IH} | R or S | | | 10 | μA |
| | PRE or CLR | $V_{CC} = \text{MAX.}$, $V_I = 2.4 \text{ V}$ | | 20 | |
| | CLK | | | -0.2 | |
| I_{IL} | R or S | | | -0.18 | mA |
| | All other | $V_{CC} = \text{MAX.}$, $V_I = 0.3 \text{ V}$ | | -0.36 | |
| I_{OS} | $V_{CC} = \text{MAX.}$ | -3 | | -15 | mA |
| I_{CC} | $V_{CC} = \text{MAX.}$, See Note 2 | | 0.76 | 1.44 | mA |

† For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

‡ All typical values are at $V_{CC} = 5 \text{ V.}$, $T_A = 25^\circ\text{C.}$

NOTE 2: With all outputs open, I_{CC} is measured with the Q and \bar{Q} outputs high in turn. At the time of measurement, the clock input is grounded.

switching characteristics, $V_{CC} = 5 \text{ V.}$, $T_A = 25^\circ\text{C}$ (see note 3)

| PARAMETER | FROM (INPUT) | TO (OUTPUT) | TEST CONDITIONS | MIN | TYP | MAX | UNIT | |
|-----------|-----------------------|----------------|--|-----|-----|-----|------|----|
| f_{max} | | | $R_L = 4 \text{ k}\Omega,$ $C_L = 50 \text{ pF}$ | 2.5 | 3 | | MHz | |
| t_{PLH} | PRE or CLR | Q or \bar{Q} | | | 35 | 75 | ns | |
| t_{PHL} | PRE or CLR (CLK high) | \bar{Q} or Q | | | 60 | 150 | ns | |
| | PRE or CLR (CLK low) | | | | 200 | | | |
| t_{PLH} | CLK | Q or \bar{Q} | | | 10 | 35 | 75 | ns |
| t_{PHL} | | | | | 10 | 60 | 150 | |

NOTE 3: See General Information Section for load circuits and voltage waveforms.

3

TTL DEVICES